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**Inspec - 1898 to date (INZZ)**

**Accession number & update**
0003660931 20070101.

**Title**
A new structural framework for parity equation-based failure detection and isolation.

**Source**
Automatica, {Automatica-UK}, March 1990, vol. 26, no. 2, p. 381-8, 22 refs, CODEN: ATCAA9, ISSN: 0005-1098, UK.

**Author(s)**
Gerlet-J, Singer-D.

**Author affiliation**
Gerlet, J., Dept. of Electr. & Comput. Eng., George Mason Univ., Fairfax, VA, USA.

**Abstract**
Describes a new framework for developing parity equations that prevent incorrect isolation decision under marginal size failures in a decision **process** that tests each residual independently. Test **thresholds** that take the noise conditions into account are set high to reduce the occurrence of false **alarms** while maintaining the algorithm's ability to detect and isolate larger failures. The method is applicable to additive failures on the measured input and output variables and to additive plant disturbances. A transformation algorithm provides a multiple of models that satisfy the isolability requirements. A search procedure utilizing this model redundancy integrates model robustness consideration into the design.

**Descriptors**
DECISION-THEORY; REDUNDANCY; RELIABILITY-THEORY; SEARCH-PROBLEMS.

**Classification codes**
C1210B Reliability-theory*;
C1140E Game-theory;
E1020 Maintenance-and-reliability*.

**Keywords**
reliability-theory; failure-isolation; parity-equation-based-failure-detection; **decision-process**; noise-conditions; additive-plant-disturbances; search-procedure; model-redundancy; model-robustness.

**Treatment codes**

T Theoretical-or-mathematical.

**Language**
English.

**Publication type**
Journal-paper.

**Availability**
CCCC: 0005-1098/90/$3.00+0.00.

**Publication year**
1990.

**Publication date**
19900300.

**Edition**
1990015.

**Copyright statement**
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**1**  **Reasoning about systems with many processes**                    ☐
◈  Steven M. German, A. Prasad Sistla
    July 1992  **Journal of the ACM (JACM)**,  Volume 39 Issue 3
    **Publisher:** ACM Press

    Full text available: 📄 pdf(4.54 MB)          Additional Information: full citation, abstract, references, citings, index terms

    Methods are given for automatically verifying temporal properties of concurrent systems
    containing an arbitrary number of finite-state processes that communicate using CCS
    actions. TWo models of systems are considered. Systems in the first model consist of a
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    definitions. For this model, a decision procedure to check whether all the executions of a
    process satisfy a given specifi ...

**2**  **A survey of structured and object-oriented software specification methods and**                    ☐
◈  **techniques**
    Roel Wieringa
    December 1998  **ACM Computing Surveys (CSUR)**,  Volume 30 Issue 4
    **Publisher:** ACM Press

    Full text available: 📄 pdf(605.26 KB)          Additional Information: full citation, abstract, references, citings, index terms, review

    This article surveys techniques used in structured and object-oriented software
    specification methods. The techniques are classified as techniques for the specification of
    external interaction and internal decomposition. The external specification techniques are
    further subdivided into techniques for the specification of functions, behavior, and
    communication. After surveying the techniques, we summarize the way they are used in
    structured and object-oriented methods and indicate ways in w ...

    **Keywords**: languages

**3**  **Automating parallel simulation using parallel time streams**                    ☐
◈  Victor Yau
    April 1999  **ACM Transactions on Modeling and Computer Simulation (TOMACS)**,  Volume
    9 Issue 2
    **Publisher:** ACM Press
    Full text available: 📄 pdf(194.69 KB)   Additional Information: full citation, abstract, references, index terms

This paper describes a package for parallel steady-state stochastic simulation that was designed to overcome problems caused by long simulation times experienced in our ongoing research in performance evaluation of high-speed and integrated-services communication networks, while maintaining basic statistical rigors of proper analysis of simulation output data. The package, named AKAROA, accepts ordinary (nonparallel) simulation programs, and alll further stages of stochastic simulation shou ...

**Keywords**: distributed simulation, interprocess communication, output analysis methodology, parallel processing, parallel simulation, parallel time streams, spectral analysis, speedup

**4**  Behavior modelling during software design

William E. Riddle, Jack C. Wileden, John H. Sayler, Alan R. Segal, Allan M. Stavely

May 1978  **Proceedings of the 3rd international conference on Software engineering ICSE '78**

**Publisher**: IEEE Press

Full text available: pdf(999.46 KB)    Additional Information: full citation, abstract, references, citings, index terms

A modelling scheme is presented which provides a medium for the rigorous, formal and abstract specification of large-scale software system components. The scheme allows the description of component behavior without revealing or requiring the description of a component's internal operation. Both collections of sequential processes and the data objects which they share may be described. The scheme is of particular value during the early stages of software system design, when the system's modu ...

**Keywords**: Desired behavior specification, Dream, Event-based models, Message transfer models, Non-procedural specification, Software design analysis, Software design languages, Software system behavior modelling

**5**  DREAM - an approach to designing large scale, concurrent software systems

Jack C. Wileden

January 1979  **Proceedings of the 1979 annual conference ACM 79**

**Publisher**: ACM Press

Full text available: pdf(731.69 KB)    Additional Information: full citation, abstract, references, citings, index terms

The Design Realization, Evaluation And Modelling (DREAM) system is an automated support system for designers of large-scale, concurrent software systems. DREAM is intended to facilitate the orderly development of such software systems by supporting high-level, abstract design descriptions and the successive modification and elaboration of incomplete descriptions. DREAM also provides a basis for formulating arguments regarding the correctness of an evolving design at any stage during its dev ...

**6**  A Quantitative Evaluation of the Feasibility of, and Suitable Hardware Architectures for, an Adaptive, Parallel Finite-Element System

Pamela Zave, George E. Cole

September 1983  **ACM Transactions on Mathematical Software (TOMS)**, Volume 9 Issue 3

**Publisher**: ACM Press

Full text available: pdf(1.36 MB)    Additional Information: full citation, references, citings, index terms

**7**

A hierarchical controller for concurrent accessing of distributed databases

Mohamed G. Gouda
August 1978 **ACM SIGARCH Computer Architecture News , ACM SIGIR Forum , ACM SIGMOD Record**, Volume 7 , 13 , 10 Issue 2 , 2 , 1
**Publisher:** ACM Press
Full text available: pdf(460.93 KB)    Additional Information: full citation, abstract, references

> An access controller for a distributed database is a (central or distributed) structure which routes access requests to the different components of the database. Such a controller is also supposed to resolve the conflicts between concurrent requests, if any, such that deadlock situations never arise.In this paper, some architectures for distributed access controllers of distributed databases are investigated. In particular, three controllers with hierarchical architectures are considered. The co ...

8 Implementing software configuration control in the structured programming environment
H. Ronald Berlack
January 1981 **ACM SIGMETRICS Performance Evaluation Review , Proceedings of the 1981 ACM workshop/symposium on Measurement and evaluation of software quality**, Volume 10 Issue 1
**Publisher:** ACM Press
Full text available: pdf(1.04 MB)    Additional Information: full citation, abstract, references, index terms

> The fundamental problems in the control of software are explored. The elements of control as they relate to communications is defined, and the implementation of these elements in solving the fundamental problems and achieving optimal control during a software development life cycle, is explained. Control is defined as a vehicle for communicating changes to established, agreed-upon baseline points, made up of documents and subsequent computer programs. By communicating change to t ...

9 The role of artificial intelligence in fault-tolerant process-control systems
F. B. Bastani, I.-R. Chen
June 1988 **Proceedings of the 1st international conference on Industrial and engineering applications of artificial intelligence and expert systems - Volume 2 IEA/AIE '88**
**Publisher:** ACM Press
Full text available: pdf(854.81 KB)    Additional Information: full citation, references, citings, index terms

10 Design of an Adaptive, Parallel Finite-Element System
Pamela Zave, Werner C. Rheinboldt
March 1979 **ACM Transactions on Mathematical Software (TOMS)**, Volume 5 Issue 1
**Publisher:** ACM Press
Full text available: pdf(1.12 MB)    Additional Information: full citation, references, citings, index terms

11 An Approach to Program Behavior Modeling and Optimal Memory Control
Percy Tzelnic, Izidor Gertner
April 1982 **Journal of the ACM (JACM)**, Volume 29 Issue 2
**Publisher:** ACM Press
Full text available: pdf(1.37 MB)    Additional Information: full citation, references, index terms

12
A transputer-based parallel Lisp implementation

M. D. Feng, C. K. Yuen
April 1992 **Proceedings of the 1992 ACM annual conference on Communications CSC
'92**
**Publisher:** ACM Press
Full text available: pdf(816.59 KB)    Additional Information: full citation, references, index terms

**Keywords**: parallel Lisp, speculative processing, transputer, tuple space

**13** A hierarchical controller for concurrent accessing of distributed databases
Mohamed G. Gouda
August 1978 **Proceedings of the fourth workshop on Computer architecture for non-
numeric processing CAW '78**
**Publisher:** ACM Press
Full text available: pdf(401.90 KB)    Additional Information: full citation, abstract, references, citings, index
terms

An access controller for a distributed database is a (central or distributed) structure which
routes access requests to the different components of the database. Such a controller is
also supposed to resolve the conflicts between concurrent requests, if any, such that
deadlock situations never arise. In this paper, some architectures for distributed access
controllers of distributed databases are investigated. In particular, three controllers with
hierarchical architectures are c ...

**14** XML access control: Access control of XML documents considering update
operations
Chung-Hwan Lim, Seog Park, Sang H. Son
October 2003 **Proceedings of the 2003 ACM workshop on XML security XMLSEC '03**
**Publisher:** ACM Press
Full text available: pdf(298.78 KB)    Additional Information: full citation, abstract, references, citings, index
terms

As a large quantity of information is presented in XML format on the Web, there are
increasing demands for XML security. Until now, research on XML security has been
focused on the security of data communication using digital signatures or encryption
technologies. As XML is also used for a data representation of data storage, XML security
comes to involve not only communication security but also managerial security.
Managerial security is guaranteed through access control, but existing XML acces ...

**Keywords**: XML document, XML update, access control

**15** An approach to software configuration control
William Bryan, Stanley Siegel, Gary Whiteleather
January 1981 **ACM SIGMETRICS Performance Evaluation Review , Proceedings of the
1981 ACM workshop/symposium on Measurement and evaluation of
software quality**, Volume 10 Issue 1
**Publisher:** ACM Press
Full text available: pdf(729.29 KB)    Additional Information: full citation, abstract, index terms

The purpose of this paper is to discuss the process by which a system's life cycle and its
associated life cycle products are managed to ensure the quality and integrity of the
system. We call this process configuration control. Although many of the ideas in this
paper are applicable to systems in general, the focus of this paper is on configuration
control of systems with software content. It is becoming apparent to many, in both
government and private ind ...

**16** Identifying different paradigms for managing information technology

Sven J. Fischer, Jan Achterberg, Tsvi G. Vinig

June 1993 **Proceedings of the 1993 conference on Computer personnel research SIGCPR '93**

**Publisher:** ACM Press

Full text available: pdf(1.79 MB)

Additional Information: full citation, abstract, references, citings, index terms

Organizations are shaped based on a number of implicit and explicit assumptions. Usually, these assumptions are made by the founder of a company. Management of Information Technology (IT) is shaped in much the same way. It is based on several assumptions how to carry out information systems development, maintenance, information services, and how to plan for and control all these activities. Based on such assumptions, the authors identify four different approaches or paradigms to management ...

**17** Transformation of data flow analysis models to object oriented design

Bruno Alabiso

January 1988 **ACM SIGPLAN Notices , Conference proceedings on Object-oriented programming systems, languages and applications OOPSLA '88**, Volume 23 Issue 11

**Publisher:** ACM Press

Full text available: pdf(1.27 MB)

Additional Information: full citation, abstract, references, citings, index terms

This paper describes a strategy to transform Data Flow Analysis into Object Oriented Design. This transformation is performed by extracting information from the Data Flow Model, by enriching with Design decision and by finally producing an Object Oriented Design Model. Semiformal transformation rules are described. Also a special notation is introduced to describe the Object Oriented Design Model. The Model used to represent Data Flow Analysis is the one originally proposed by Yourdon, comp ...

**18** Information systems security design methods: implications for information systems development

Richard Baskerville

December 1993 **ACM Computing Surveys (CSUR)**, Volume 25 Issue 4

**Publisher:** ACM Press

Full text available: pdf(3.44 MB)

Additional Information: full citation, abstract, references, citings, index terms

The security of information systems is a serious issue because computer abuse is increasing. It is important, therefore, that systems analysts and designers develop expertise in methods for specifying information systems security. The characteristics found in three generations of general information system design methods provide a framework for comparing and understanding current security design methods. These methods include approaches that use checklists of controls, divide functional req ...

**Keywords**: checklists, control, integrity, risk analysis, safety, structured systems analysis and design, system modeling

**19** Behavioral control for real-time simulated human agents

John P. Granieri, Welton Becket, Barry D. Reich, Jonathan Crabtree, Norman I. Badler

April 1995 **Proceedings of the 1995 symposium on Interactive 3D graphics SI3D '95**

**Publisher:** ACM Press

Full text available: pdf(1.11 MB)

Additional Information: full citation, abstract, references, citings, index terms

A system for controlling the behaviors of an interactive human-like agent, and executing them in real-time, is presented. It relies on an underlying model of continuous behavior as well as a discrete scheduling mechanism for changing behavior over time. A multiprocessing framework executes the behaviors and renders the motion of the agents in real-time. Finally we discuss the current state of our implementation and some areas of future work.

**20** Performance analysis of MSP: feature-rich high-speed transport protocol
Thomas F. La Porta, Mischa Schwartz
December 1993 **IEEE/ACM Transactions on Networking (TON),** Volume 1 Issue 6
**Publisher:** IEEE Press
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**Accession number & update**
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**Title**
 Artificial immunity based management system for a semiconductor production line.
**Conference information**
 1997 IEEE International Conference on Systems, Man, and Cybernetics. Computational Cybernetics and Simulation, Orlando, FL, USA, 12-15 Oct. 1997.
 Sponsor(s): Syst., Man, & Cybernetics Soc. IEEE.
**Source**
 1997 IEEE International Conference on Systems, Man, and Cybernetics. Computational Cybernetics and Simulation (Cat. No.97CH36088-5), 1997, vol.1, p. 851-5 vol.1, 6 refs, pp. 5 vol. 4535, ISBN: 0-7803-4053-1.
 Publisher: IEEE, New York, NY, USA.
**Author(s)**
 Mori-K, Tsukiyama-M, Fukuda-T.
**Author affiliation**
 Mori, K., Tsukiyama, M., Ind. Electron. & Syst. Labs., Mitsubishi Electr. Corp., Hyogo, Japan.

**Abstract**
 A semiconductor production line is a large scale and complex system. It is considered to be difficult to **control** because there exist lots of malfunctions such as maintenance of equipment, equipment break-down and imbalance of WIP to disturb production of wafers in the semiconductor production system. Methods and systems using simulations or expert systems have been used to solve these disturbances, the but semiconductor production environments change dynamically and therefore these methods alone do not yield a perfect **control** system. This paper presents a method applying an artificial immunity based system described by multi-agent nets, that adapts itself to a dynamical environment.

**Descriptors**
 INTEGRATED-CIRCUIT-MANUFACTURE; LARGE-SCALE-SYSTEMS; PETRI-NETS; PRODUCTION-CONTROL.
**Classification codes**
 B0170E Production-facilities-and-engineering*;
 B2570 Semiconductor-integrated-circuits;
 B0250 Combinatorial-mathematics;
 C1290F Systems-theory-applications-in-industry*;

C1340B Multivariable-control-systems;
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E1010 Production-management;
E1520 Manufacturing-processes;
E1540 Systems-theory-applications;
E1550 Control-technology-and-theory;
E3644A Semiconductor-industry.

**Keywords**

artificial-immunity-based-management-system; semiconductor-production-line; large-scale-complex-system; malfunctions; maintenance; equipment-break-down; WIP-imbalance; **wafer-production;** expert-systems; multi-agent-nets; colored-Petri-nets; dynamical-environment.

**Treatment codes**

T Theoretical-or-mathematical.

**Language**

English.

**Publication type**

Conference-paper.

**Availability**

CCCC: 0 7803 4053 1/97/$10.00.

**Digital object identifier**

10.1109/ICSMC.1997.626207.

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